제 29회 한국반도체학술대회 The 29th Korean Conference on Semiconductors

2022년 1월 24일(월)~ 26일(수) | 강원도 하이원 그랜드호텔(컨벤션타워)

2022년 1월 26일(수), 09:00-10:30

Room F (스페이드 I, 6층)

G. Device & Process Modeling, Simulation and Reliability 분과 [WF1-G] Memory Devices and Advanced Modeling

좌장: 나현철 상무(DB 하이텍), 김성호 교수(세종대학교)

WF1-G-1 09:00-09:15	Analysis of Short-Term Retention in 3-D NAND Flash Memory Using Charge Control Pulse Scheme Donghwi Kim ¹ , GilSang Yoon ¹ , DongHyun Go ¹ , Junghun Park ¹ , Jungsik Kim ² , and Jeong-Soo Lee ¹ ¹ Department of Electrical Engineering, POSTECH, ² Division of Electrical Engineering, Gyeongsang National University
WF1-G-2 09:15-09:30	Scaling Analysis of NbO _x -Threshold Switching Devices Hyun Wook Kim ^{1,2} , Sol Jin ² , Heebum Kang ¹ , Eun Ryeong Hong ^{1,2} , and Jiyong Woo ^{1,2} ¹ School of Electronic and Electrical Engineering, Kyungpook National University, ² School of Electronics Engineering, Kyungpook National University
WF1-G-3 09:30-09:45	Variation of Electrical and Memory Characteristics of Non-Circular Cell in 3D- NAND Flash Memory DongHyun Go ¹ , GilSang Yoon ¹ , Jounghun Park ¹ , Dongwhi Kim ¹ , Jungsik Kim ² , and Jeong-Soo Lee ¹ ¹ Department of Electrical Engineering, POSTECH, ² Division of Electrical Engineering, Gyeongsang National University
WF1-G-4 09:45-10:00	Accurate Implementation of the Bernoulli Function for the Scharfetter-Gummel Scheme Jeong-Hyeon Do and Sung-Min Hong School of Electrical Engineering and Computer Science, GIST
WF1-G-5 10:00-10:15	Physicochemical modeling of conformal coating on periodical high aspect ratio porous media via atomic layer deposition Nhat-Minh Phung ^{1,2} , Sun-Young Park ^{1,3} , Minh-Tan Ha ^{1,2} , Soonil Lee ² , Se-Hun Kwon ³ , and Seong Min Jeong ¹ ¹ Energy Efficiency Materials Center, KICET, ² Department of Materials Science and Engineering, Changwon National University, ³ School of Materials Science and Engineering, Pusan National University
WF1-G-6 10:15-10:30	TCAD Analysis of Single-Photon Avalanche Diodes in CMOS Technology Won-Yong Ha ¹ , Woo-Young Choi ¹ , and Myung-Jae Lee ² ¹ Department of Electrical and Electronic Engineering, Yonsei University, ² Post-Silicon Semiconductor Institute, KIST